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1 Breakpoint debugging mechanism for microprocessor design

Wang Danghui; Gao Deyuan; Li Tao;
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2003

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2 A knowledge base approach to the specification of real time system requirements

Birch, M.; Whiteley, K.;
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3 Setting break-points in distributed time-triggered architecture

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4 Breaking an application specific instruction-set processor: the first towards embedded software testing

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12 A proposed real-time ADA test

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Pages:932 - 936 vol.2

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